TOCHLO ZOOLEOOL

FIG. 1

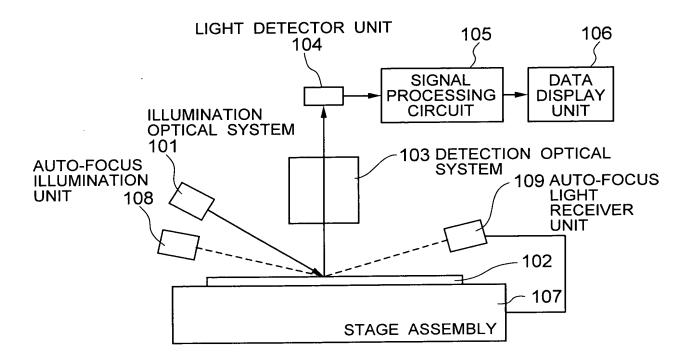
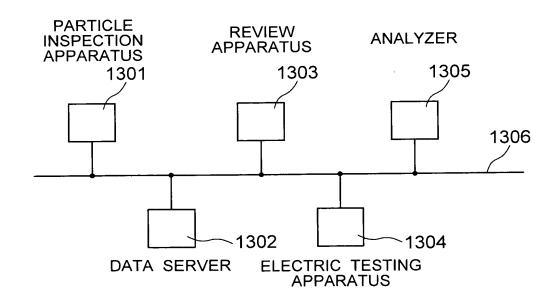


FIG. 2



Robert C. Colwell, Reg. No. 27,431 Applicant: Hidetoshi Nishiyama, et al.

e: Method and Its Apparatus for Inspecting Particle Atty Docket No. 16869S-032100 Sheet 2 of 21

FIG. 3A

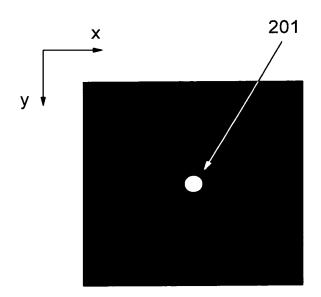
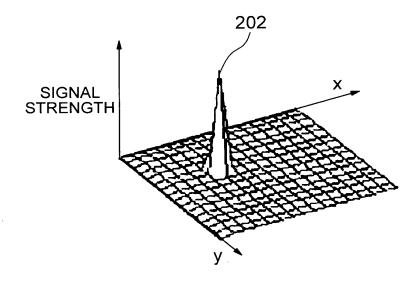


FIG. 3B



And the first for the time that the first that he half the he half half Sheet 3 of 21

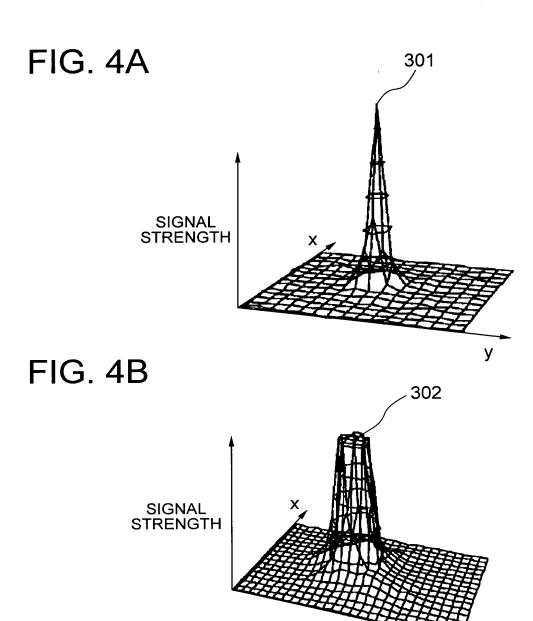
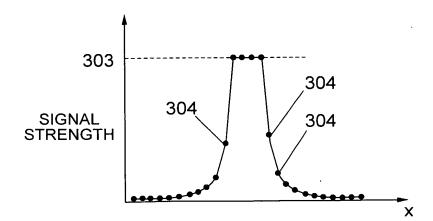


FIG. 4C



Applicant: Hidetoshi Nishiyama, et al. : Method and Its Apparatus for Inspecting Particle Atty Docket No. 16869S-032100

Sheet 4 of 21

FIG. 5A

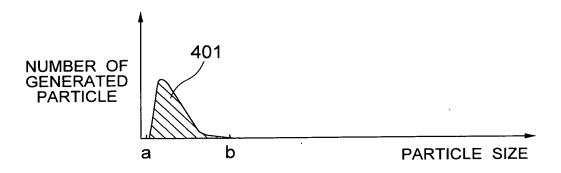


FIG. 5B

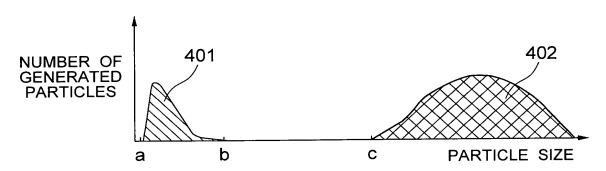
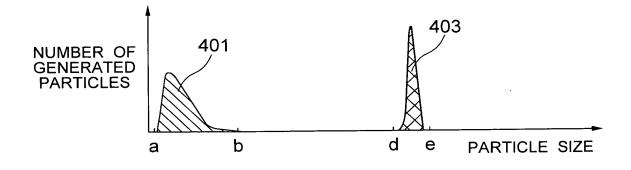


FIG. 5C



A. H. The land of the land that the land h had 2. h th th

Applicant: Hidetoshi Nishiyama, et al. lle: Method and Its Apparatus for Inspecting Partic Atty Docket No. 16869S-032100

Sheet 5 of 21

FIG. 6

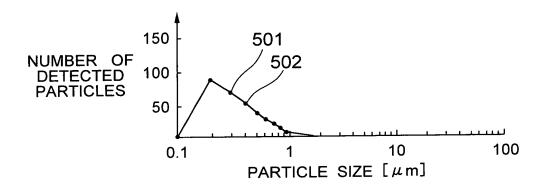
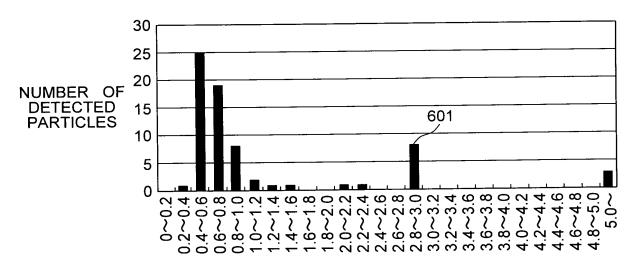


FIG.7



PARTICLE SIZE [µm]

Robert C. Colwell, Reg. No. 27,451

Applicant: Hidetoshi Nishiyama, et al. Method and Its Apparatus for Inspecting Particles

Atty Docket No. 16869S-032100

Sheet 6 of 21

FIG. 8A

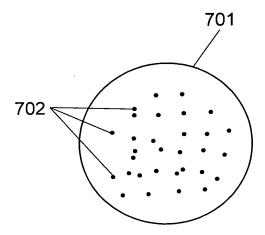
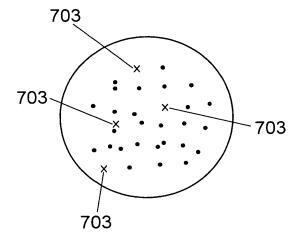


FIG. 8B



time the first to the first that the Hall de la California Sheet 7 of 21

FIG. 9A

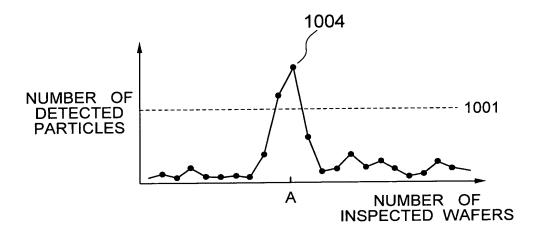


FIG. 9B

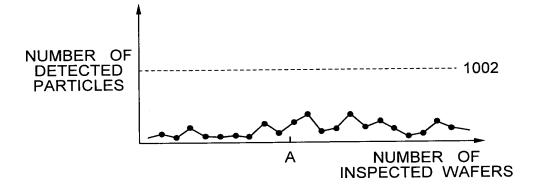
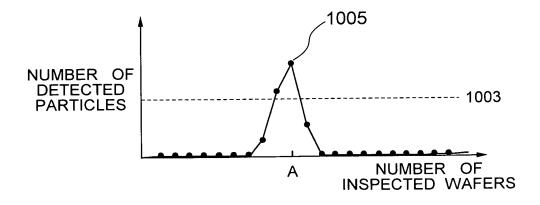


FIG. 9C



ngarago, ngayna

Applicant: Hidetoshi Nishiyama, et al.

ttle: Method and Its Apparatus for Inspecting Partic

Atty Docket No. 16869S-032100

Sheet 8 of 21

FIG. 10

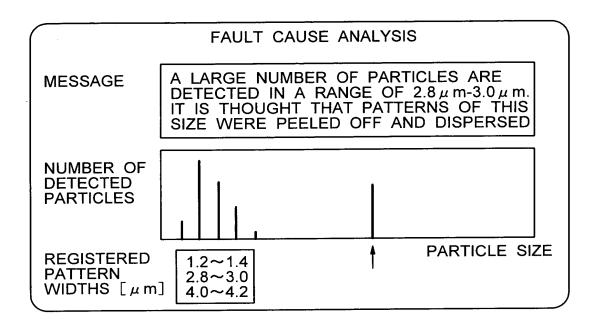
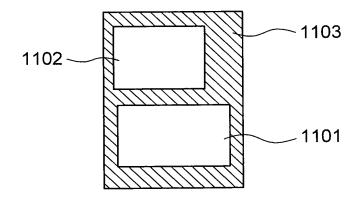


FIG. 11



DOGELOGY INSTERD

Sheet 9 of 21

FIG. 12A

the test test to the test test test test

He that the the that

FIG. 12B

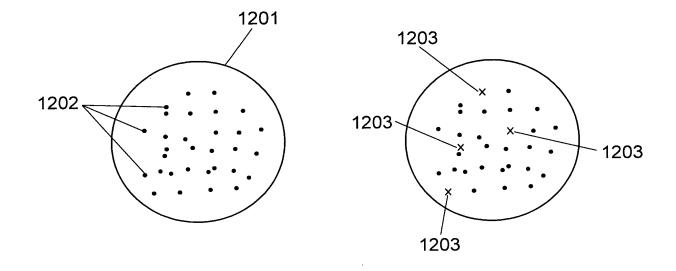
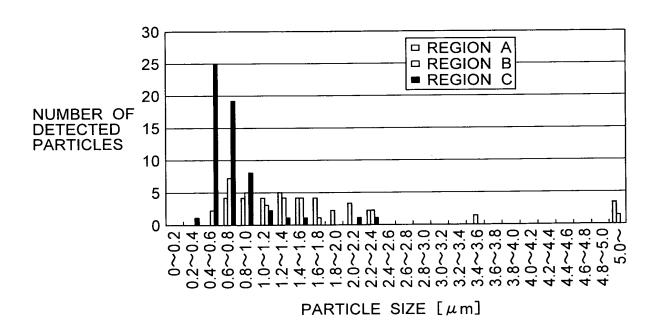


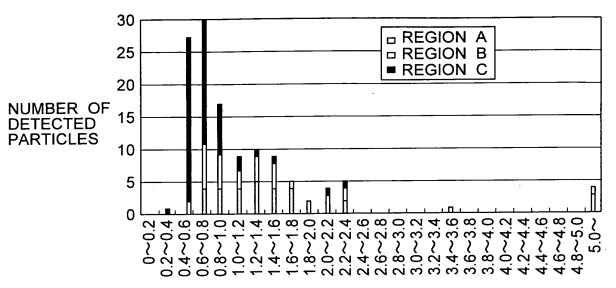
FIG. 13



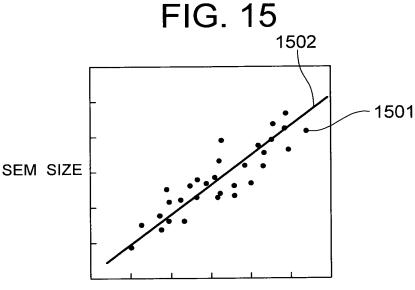
Applicant: Hidetoshi Nishiyama, et al. Method and Its Apparatus for Inspecting Particle

Atty Docket No. 16869S-032100 Sheet 10 of 21

FIG. 14

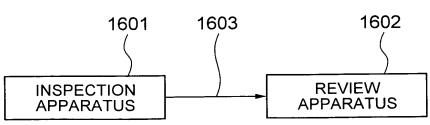


PARTICLE SIZE [μ m]



MAXIMUM SIGNAL STRENGTH VALUE

FIG. 16



COORDINATES, PARTICLE SIZES, REVIEW SCALING FACTOR

Applicant: Hidetoshi Nishiyama, et al. Method and Its Apparatus for Inspecting Particle Atty Docket No. 16869S-032100

Sheet 11 of 21

FIG. 17A

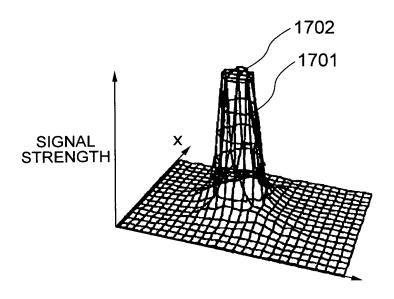


FIG. 17B

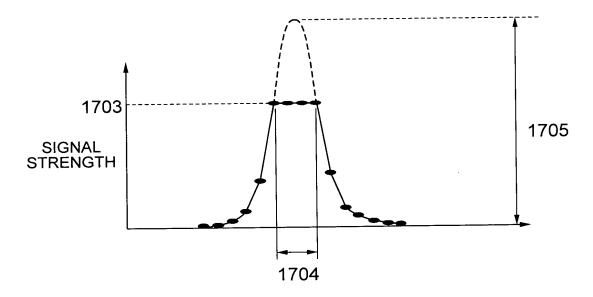
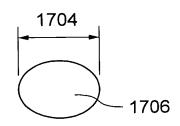


FIG. 17C



Applicant: Hidetoshi Nishiyama, et al. e: Method and Its Apparatus for Inspecting Particle

Atty Docket No. 16869S-032100 Sheet 12 of 21

FIG. 18A

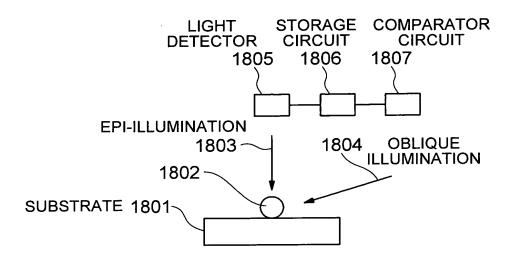
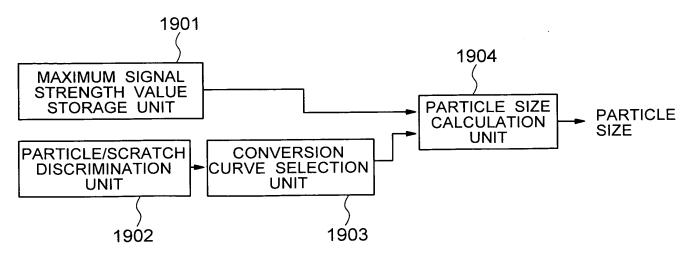


FIG. 18B

	DIFFERENECE IN SCATTERED LIGHT DEPENDING ON ILLUMINATING DIRECTION		SCATTERED LIGHT AMOUNT RATIO
	EPI- ILLUMINATION	OBLIQUE ILLUMINATION	(EPI/OBLIQUE)
PARTICLES	AMOUNT OF SCATTERED LIGHT:LARGE	AMOUNT OF SCATTERED LIGHT:LARGE	SMALL
SCRATCHES	AMOUNT OF SCATTERED LIGHT:LARGE	AMOUNT OF SCATTERED LIGHT:SMALL	LARGE

FIG. 19



1=

tle: Method and Its Apparatus for Inspecting Partic Atty Docket No. 16869S-032100

Sheet 48 of 21

FIG. 20

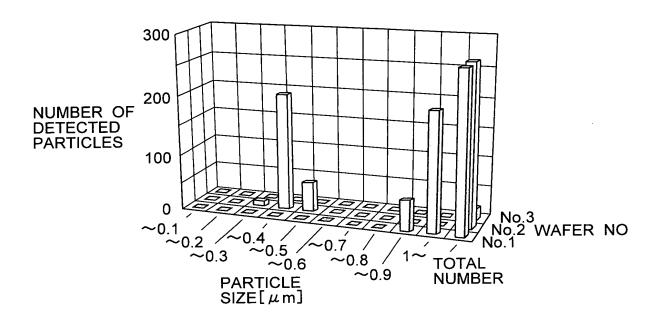
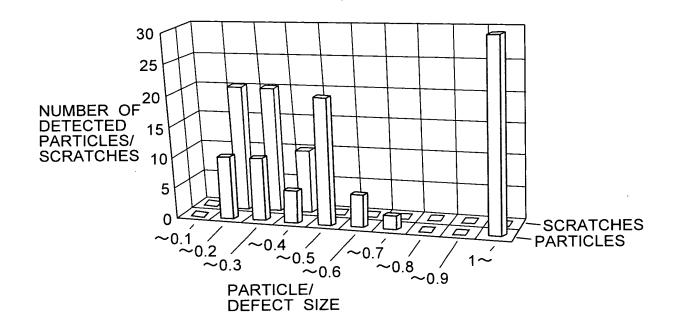


FIG. 21



 Applicant: Hidetoshi Nishiyama, et al.
tle: Method and Its Apparatus for Inspecting Particle
Atty Docket No. 16869S-032100

Sheet 45 of 21

FIG. 22

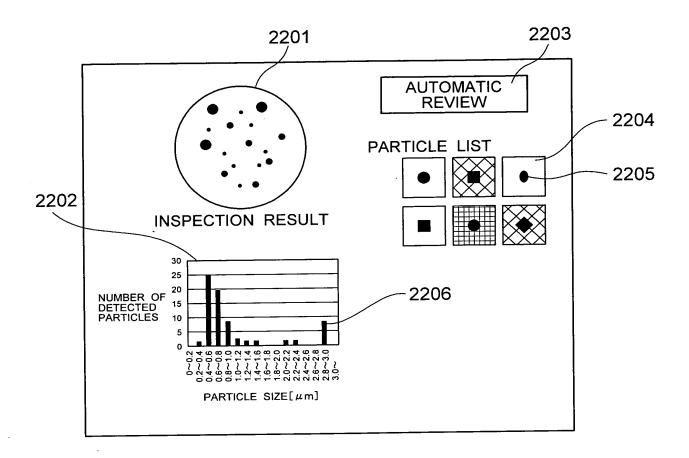
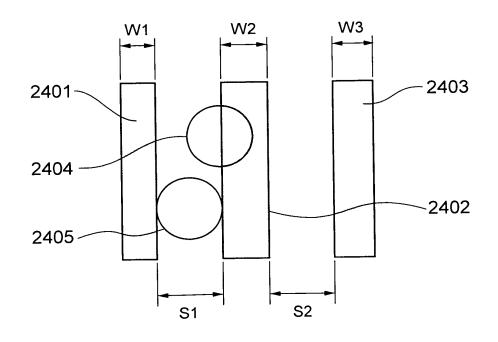


FIG. 23

CELET COL COL CITY



Applicant: Hidetoshi Nishiyama, et al.

tle: Method and Its Apparatus for Inspecting Partil

Atty Docket No. 16869S-032100

Sheet 44 of 21

FIG. 24

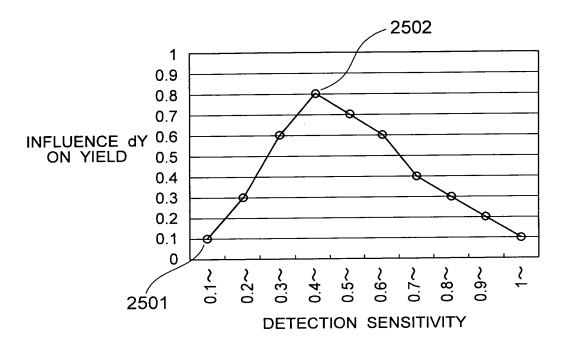
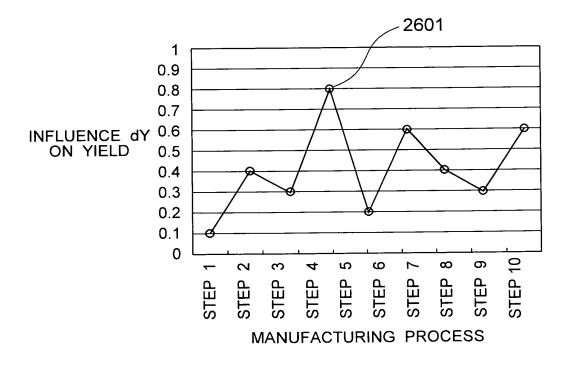


FIG. 25

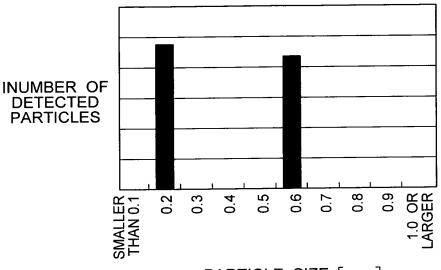


In the fact the test that

Applicant: Hidetoshi Nishiyama, et al. tle: Method and Its Apparatus for Inspecting Partid Atty Docket No. 16869S-032100

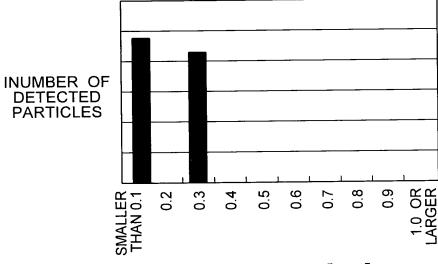
Sheet 45 of 21

FIG. 26



PARTICLE SIZE [μ m]

FIG. 27



PARTICLE SIZE [μ m]

Applicant: Hidetoshi Nishiyama, et al.

Fitle: Method and Its Apparatus for Inspecting Parl

Atty Docket No. 16869S-032100

Sheet 19 of 21

FIG. 28

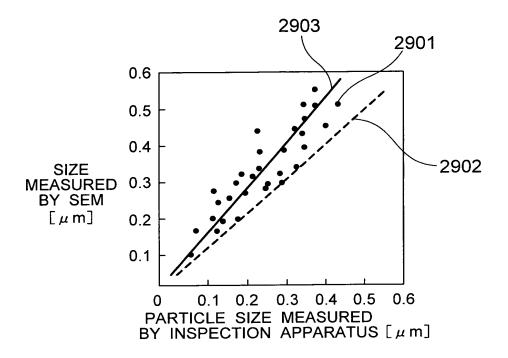
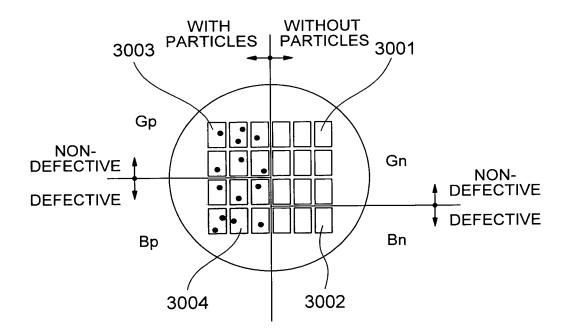


FIG. 29



Applicant: Hidetoshi Nishiyama, et al.

tle: Method and Its Apparatus for Inspecting Partic

Atty Docket No. 16869S-032100

Sheet 16 of 21

FIG. 30A

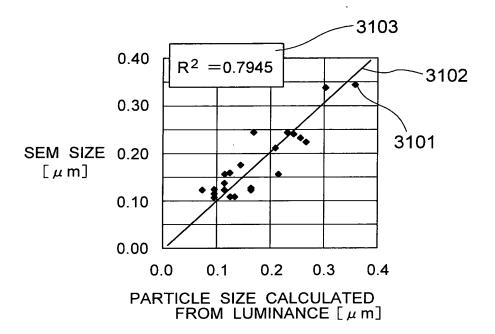
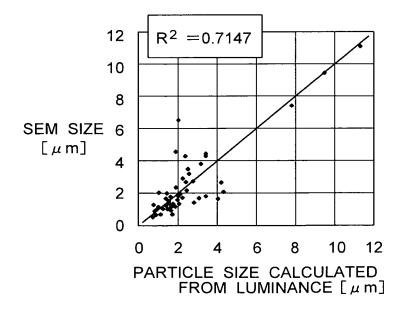


FIG. 30B



Applicant: Hidetoshi Nishiyama, et al.

tle: Method and Its Apparatus for Inspecting Partic Atty Docket No. 16869S-032100 Sheet 17 of 21

FIG. 31

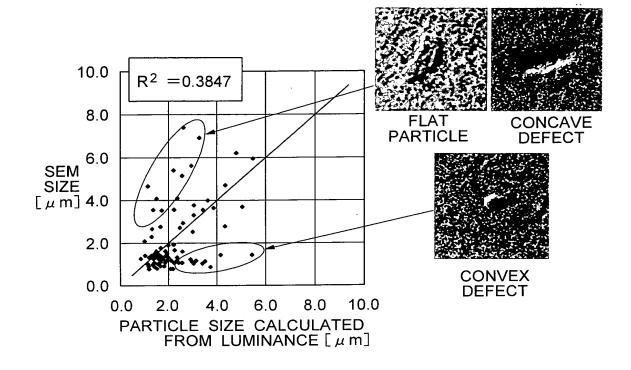
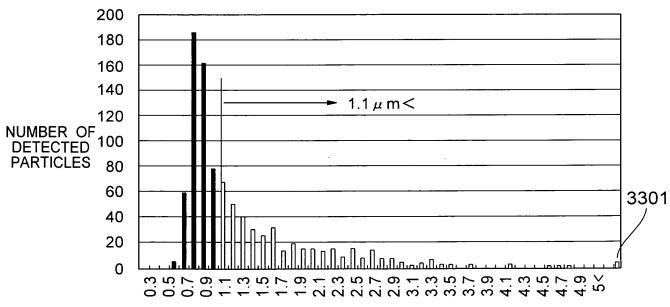


FIG. 32



PARTICLE SIZE CALCULATED FROM LUMINANCE [μ m] Applicant: Hidetoshi Nishiyama, et al.
tie: Method and Its Apparatus for Inspecting Partic
Atty Docket No. 16869S-032100

Sheet 20 of 21

FIG. 33A

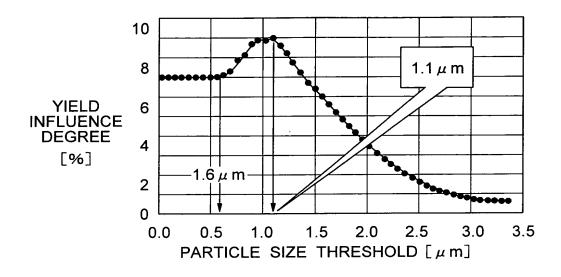


FIG. 33B

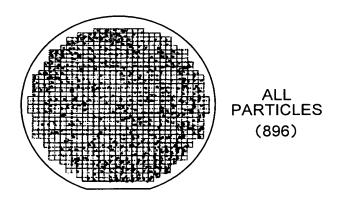
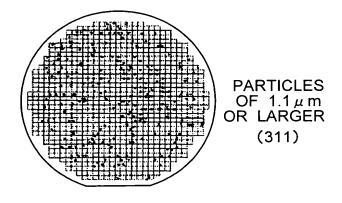
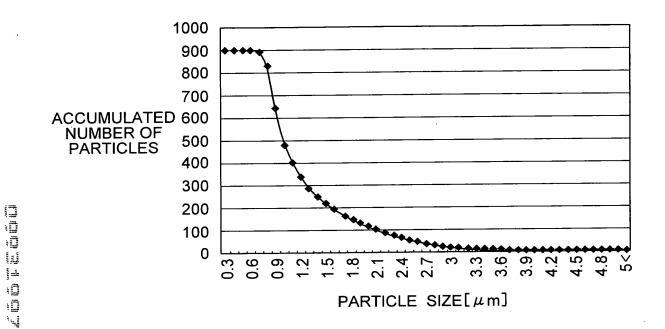


FIG. 33C



Atty Docket No. 16869S-032100 Sheet 21 of 21

FIG. 34



The Last Line and the tent

FIG. 35

